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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Complete if Known				
Application Number	1017731077			
Filing Date	February 5, 2004			
First Named Inventor	Treado			
Art Unit	2877			
Examiner Name	. Lauch man, Layla b.			
Attorney Docket Number	030697			

	T 61	r = =		DOCUMENTS	
Examiner Initials*	Cite No.	Document Number Number-Kind Code ² (4 known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
LL.	A	^{US-} 5,194,912	03-16-1993	Batchelder et al.	
ee_	B	^{US-} 5,377,003	12-27-1994	Lewis et al.	
	0	^{US-} 5,377,004	12-27-94	Owen et al.	
XX.	P	^{US-} 5,442,438	08-15-1995	Batchelder et al.	
X	E	^{US-} 5,493,443	02-20-1996	Simon et al.	
Se	F	^{US-} 5,528,393	06-18-1996	Sharp et al.	
	6	^{US-} 5,623,342	04-22-1997	Baldwin et al.	
	H	^{US-} 5,689,333	11-18-1997	Batchelder et al.	
4	I	^{US-} 5,710,626	01-20-1998	O'Rourke et al.	· · · · · · · · · · · · · · · · · · ·
	1	^{US-} 5,862,273	01-19-1999	Pelletier	
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	N	us- 6,002,476	12-14-1999	Treado	
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RI	0	^{US-} 6,571,117	05-27-2003	Marbach	
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Examiner Initials*	Cite No.1	Foreign Patent Document	Publication Date	Mame of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages	Τ
00		Country Code ³ "Number ⁴ "Kind Code ³ (# known)	MM-DD-YYYY	The state of the s	Or Relevant Figures Appear	T
	1	PCT/CA98/00092	08-13-1998	Raz et al.		┢
8	U	WO95/11624	05-1995	Feld et al.		Г
X	V	EP 0174778 B1	11-30-88	Mumford		
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	Application Number	. 10/773,077 .
INFORMATION DISCLOSURE	Filing Date	Feb 5, 2004
	First Named Inventor	Treado
STATEMENT BY APPLICANT	Art Unit	2877
(Use as many sheets as necessary)	Examiner Name	Lauchman, hayla 6,
neet 2 of 2	Attorney Docket Number	030687

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Examiner Initiats*	Cite No.1	Document Number Number-Kind Code ² (* Answer)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	
XC	W	^{US-} 6,274,871	08-14-2001	Dukor et al.		
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R.	2	^{US-} 6,530,882	03-11-2003	Farkas et al.		
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	Application Number	1/0/773,077
INFORMATION DISCLOSURE	Filing Date	Feb 5, 2004
	First Named Inventor	Treado
STATEMENT BY APPLICANT	Art Unit	. 2877
(Use as many sheets as necessary)	Examiner Name	Lauchman, Layla G
 Sheet 3 of 6	Attorney Docket Number	1030687

				T DOCUMENTS	
Examiner Initials*	Cite No.	Document Number Number-Kind Code ^{2 (f known)}	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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R	UЙ	^{US-} 4,802,760	02-07-1989	Inoue et al.	
K_	٧V	^{US-} 2004/0004715	01-08-2004	Tuschel et al.	
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		FOREIC	ON PATENT DOCU	MENTS		
Examiner Initials*	Cite No.1	Foreign Patent Document	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages	
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Examiner Signature		Sales S.	waler	Date Considered	1/25/0	6

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Substitute for form 1449/PTO		Complete if Known
	Application Number	10(773,077
NFORMATION DISCLOSURE	Filing Date	February 5, 2004
STATEMENT BY APPLICANT	First Named Inventor	Treado
(Use as many sheets as necessary)	Art Unit	2877
	Examiner Name	Lauchman, hayla G.

Attorney Docket Number

Sheet

		NON PATENT LITERATURE DOCUMENTS	
Examiner Initials*	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
SC	μW	SKINNER et al. "Remote Raman Microimaging Using An AOTF and a Spartially Coherent Microfiber Optical Probe," Applied Spectroscopy, Vol. 50 No. 8, (1996) pp.1007- 1014.	
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Examiner Date Signature Considered

^{&#}x27;EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation in not in conformance and not considered. Include copy of this form with next communication to applicant.

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	Application Number	10/773,077	
INFORMATION DISCLOSURE	Filing Date	February 5, 2004	
STATEMENT BY APPLICANT	First Named Inventor	Treado	
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,	Examiner Name	. Lauch man, Layla G.	
Sheet 5 of - 8	Attorney Docket Number	030687	

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	F! 6' A' I' J' K' L' W	Cite No. Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published. F. CHRISTOFIDES et al., "Reconstruction Mechanisms in lon Implanted and Annealed Silicon Wafers," Defect and Diffusion Forum, Vols. 117-118 (1985) pp. 45-64 G. ISHIOKA et al., "Reduction in Raman Intensity of Si (1 1 1) Due to Defect Formation During Ion Irradiation," Solid State Communications, Vol. 96, No. 6 (1995) pp. 387-390. P. DEY et al., "Raman Scattering Characterization of Si(100) Implanted With Mega-Electron-Volt Sb", Journal of Applied Physics 87(3) 1 February 2000, pp. 1110-1116. J. JAIN et al., "Raman Scattering From Ion-Implanted Silicon," Physical Review B., Vol. 32, No. 10, 15 November 1985, pp. 6688-6691. J. DEWILTON et al., "Raman Spectroscopy For NonDestructive Depth Profile Studies Of Ion Implantation In Silicon", J. Electrochem. Soc.: Solid State Science And Technology, May 1986, pp. 988-993. K. ZHANG et al., "Details of Damage Profile in Self-Ion-Implanted Silicon," Vol. 25 Journal of Raman Spectroscopy, (1994) pp. 515-520.

Examiner		Date	<u> </u>
Signature		Considered	
ACVALUNICO I	W. L. C.		<u></u>

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	Examiner Name	Lauchman, Layla G.		
Sheet 6 of 78	Attorney Docket Number	030687		

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Examiner	Cite	NON PATENT LITERATURE DOCUMENTS	
Initials*	No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
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Sheet 7 of 7	Attorney Docket Number	1030687	

		NON PATENT LITERATURE DOCUMENTS	
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^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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		NON PATENT LITERATURE DOCUMENTS	
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
A	DDI	MILLER, et al., "Multispectral Imaging with a Liquid Crystal Tunable Filter," SPIE, Vol. 2345 (1995), pp. 354-365.	
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